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IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF : DATE ALLOWED: JUNE 30, 2006
YOSHIYUKI TANAKA, ET AL. : EXAMINER: CHUNG, P.
SERIAL NO: 10/752,504 :
FILED: JANUARY 8, 2004 : GROUP ART UNIT: 2138
FOR: SEMICONDUCTOR INTEGRATED :
CIRCUIT INCLUDING OPERATION
TEST CIRCUIT AND OPERATION TEST
METHOD THEREOF

AMENDMENT UNDER 37 C.F.R. §1.312

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Prior to patent issuance, please amend the above-identified application as follows:

Amendments to the Drawings begin on page 2 of this paper and include an attached replacement sheet.

Remarks begin on page 3 of this paper.